

RoHS Compliant Product  
A suffix of "-C" specifies halogen & lead-free

## DESCRIPTION

These miniature surface mount MOSFETs utilize a high cell density trench process to provide low  $R_{DS(on)}$  and to ensure minimal power loss and heat dissipation. Typical applications are DC-DC converters and power management in portable and battery-powered products such as computers, printers, PCMCIA cards, cellular and cordless telephones.

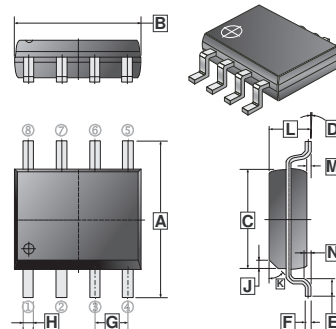
## FEATURES

- Low  $R_{DS(on)}$  provides higher efficiency and extends battery life.
- Low thermal impedance copper leadframe SOP-8 saves board space.
- Fast switching speed.
- High performance trench technology.

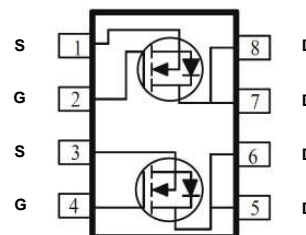
## PACKAGE INFORMATION

Package	MPQ	Leader Size
SOP-8	2.5K	13 inch

## SOP-8



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	5.80	6.20	H	0.35	0.49
B	4.80	5.00	J	0.375 REF.	
C	3.80	4.00	K	45°	
D	0°	8°	L	1.35	1.75
E	0.40	0.90	M	0.10	0.25
F	0.19	0.25	N	0.25 REF.	
G	1.27 TYP.				



## MAXIMUM RATINGS ( $T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>1</sup>	$I_D$	$T_A=25^\circ\text{C}$	8.3
		$T_A=70^\circ\text{C}$	6.8
Pulsed Drain Current <sup>2</sup>	$I_{DM}$	50	A
Continuous Source Current (Diode Conduction) <sup>1</sup>	$I_S$	2.3	A
Total Power Dissipation <sup>1</sup>	$P_D$	$T_A=25^\circ\text{C}$	2.1
		$T_A=70^\circ\text{C}$	1.3
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55~150	$^\circ\text{C}$
<b>Thermal Resistance Rating</b>			
Maximum Junction to Ambient <sup>a</sup>	$t \leq 10$ sec	$R_{\theta JA}$	62.5
	Steady-State		110

### Notes

- 1 Surface Mounted on 1" x 1" FR4 Board.
- 2 Pulse width limited by maximum junction temperature.

**ELECTRICAL CHARACTERISTICS** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	30	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$
Gate-Threshold Voltage	$V_{GS(th)}$	1	-	-	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
Gate-Body Leakage	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{DS}=0, V_{GS}=20\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS}=24\text{V}, V_{GS}=0$
		-	-	25	$\mu\text{A}$	$V_{DS}=24\text{V}, V_{GS}=0, T_J=55^\circ\text{C}$
On-State Drain Current <sup>1</sup>	$I_{D(on)}$	20	-	-	A	$V_{DS}=5\text{V}, V_{GS}=10\text{V}$
Drain-Source On-Resistance <sup>1</sup>	$R_{DS(ON)}$	-	-	22	m $\Omega$	$V_{GS}=10\text{V}, I_D=8.3\text{A}$
		-	23	27		$V_{GS}=4.5\text{V}, I_D=7.3\text{A}$
Forward Transconductance <sup>1</sup>	$g_{fs}$	-	40	-	S	$V_{DS}=15\text{V}, I_D=8.3\text{A}$
Diode Forward Voltage	$V_{SD}$	-	0.7	-	V	$I_S=2.3\text{A}, V_{GS}=0$
Pulsed Source Current (BodyDiode) <sup>1</sup>	$I_{SM}$	-	5	-	A	
<b>Dynamic <sup>2</sup></b>						
Total Gate Charge	$Q_g$	-	20	-	nC	$I_D=10\text{A}$ $V_{DS}=15\text{V}$ $V_{GS}=5\text{V}$
Gate-Source Charge	$Q_{gs}$	-	7.0	-		
Gate-Drain Charge	$Q_{gd}$	-	7.0	-		
Input Capacitance	$C_{iss}$	-	1317	-	pF	N-Channel $V_{DS}=15\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$
Output Capacitance	$C_{oss}$	-	272	-		
Turn-On Delay Time	$T_{d(on)}$	-	20	-	nS	$V_{DD}=25\text{V}$ $I_D=1\text{A}$ $V_{GEN}=10\text{V}$ $R_L=25\Omega$
Rise Time	$T_r$	-	9	-		
Turn-Off Delay Time	$T_{d(off)}$	-	70	-		
Fall Time	$T_f$	-	20	-		

Notes

- 1 Pulse test :  $PW \leq 300\mu\text{s}$  duty cycle  $\leq 2\%$ .
- 2 Guaranteed by design, not subject to production testing.